

<b>Notice of References Cited</b>	Application/Control No. 10/798,658		Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner J. Derek Rutten		Art Unit 2192	Page 1 of 1

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*	B	US-2005/0234993 A1	10-2005	Ordille et al.	707/104.1
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lucca et al., "Testing Web Applications", 2002, IEEE, Proceedings of the International Conference on Software Maintenance (ICSM'02), pp. 310-319
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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